Notice of References Cited	Application/Control No. 09/460,844	Applicant(s)/Patent Under Reexamination HEKMATPOUR, AMIR	
	Examiner Hugh Jones	Art Unit 2128	Page 1 of 1

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	M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.